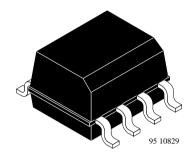
# **SMD** Optocoupler with Phototransistor Output

#### Description

The TCMT1020 Series consist of a gallium arsenid infrared emitting diode, optically coupled to a silicon NPN epitaxial planar transistor in a 8 lead SOIC package.



#### Applications

- Computer peripheral interface
- Microprocessor system interface

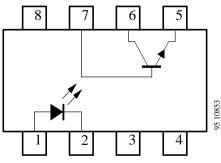
- Hybride substrates that require high density mounting
- DC/DC converter

#### Features

- Current Transfer Ration selected into 4 groups specified at I<sub>F</sub> = 10 mA
- Test isolation voltage between input and output V<sub>IO</sub> (RMS): 2.5 kV
- 8 lead package, similar SOIC-8
- Minimum V<sub>(BR)CEO</sub> of 90 V guaranteed

- Suitable for cleaning process without chemical solvent
- Soldering methods according to CECC 00802 table 1, class B or C
- Low temperature coefficient of CTR
- Base connected

#### **Pin Connection**



# **Absolute Maximum Ratings**

#### **Input (Emitter)**

Parameters	Test Conditions	Symbol	Value	Unit
Reverse voltage		V <sub>R</sub>	5	V
Forward current		IF	60	mA
Forward surge current	$t_p \le 10 \ \mu s$	I <sub>FSM</sub>	3	А
Power dissipation	$T_{amb} \le 25^{\circ}C$	P <sub>tot</sub>	100	mW
Junction temperature		Ti	125	°C

#### **Output (Detector)**

Parameters	Test Conditions	Symbol	Value	Unit
Collector base voltage		V <sub>CBO</sub>	90	V
Collector emitter voltage		V <sub>CEO</sub>	90	V
Emitter collector voltage		V <sub>ECO</sub>	7	V
Collector current		I <sub>C</sub>	50	mA
Collector peak current	$t_p/T = 0.5, t_p \le 10 \text{ ms}$	I <sub>CM</sub>	100	mA
Power dissipation	$T_{amb} \le 25^{\circ}C$	P <sub>tot</sub>	150	mW
Junction temperature		Tj	125	°C

#### Coupler

Parameters	Test Conditions	Symbol	Value	Unit
AC isolation test voltage (RMS)		V <sub>IO</sub> <sup>1)</sup>	2.5	kV
Total power dissipation	$T_{amb} \le 25^{\circ}C$	P <sub>tot</sub>	250	mW
Ambient temperature range		T <sub>amb</sub>	-55 to +100	°C
Storage temperature range		T <sub>stg</sub>	-55 to +125	°C
Soldering classification	single wave, $t \le 10$ s	T <sub>sd</sub>	260	°C

<sup>1)</sup> related to standard climate 23/50 DIN 50014

### **Electrical Characteristics**

#### $T_{amb} = 25^{\circ}C$

# Input (Emitter)

Parameters	Test Conditions	Туре	Symbol	Min.	Тур.	Max.	Unit
Forward voltage	$I_F = 50 \text{ mA}$		V <sub>F</sub>		1.25	1.6	V
Breakdown voltage	$I_R = 100 \ \mu A$		V <sub>(BR)</sub>	5			V
Junction capacitance	$V_{R} = 0, f = 1 MHz$		Ci		50		pF

#### **Output (Detector)**

Parameters	Test Conditions	Туре	Symbol	Min.	Тур.	Max.	Unit
Collector base breakdown voltage	$I_C = 100 \ \mu A$		V <sub>(BR)CB0</sub>	90			V
Collector emitter breakdown voltage	$I_C = 1 mA$		V <sub>(BR)CEO</sub>	90			V
Emitter collector breakdown voltage	$I_E = 100 \ \mu A$		V <sub>(BR)ECO</sub>	7			V
Collector emitter cut-off current	$V_{CE} = 10 \text{ V},$ I <sub>F</sub> = 0		I <sub>CEO</sub>			50	nA

#### Coupler

Parameters	Test Conditions	Туре	Symbol	Min.	Тур.	Max.	Unit
AC isolation test voltage (RMS)	f = 50 Hz, t = 1 s		V <sub>IO</sub>	2.5			kV
Collector emitter saturation voltage	$I_{\rm F} = 10 \text{ mA},$ $I_{\rm C} = 1 \text{ mA}$		V <sub>CEsat</sub>			0.3	V
Cut-off frequency	$V_{CE} = 5 \text{ V},$ $I_F = 10 \text{ mA},$ $R_L = 100 \Omega$		$f_{C}$		110		kHz
Coupling capacitance	f = 1 MHz		Ck		0.3		pF

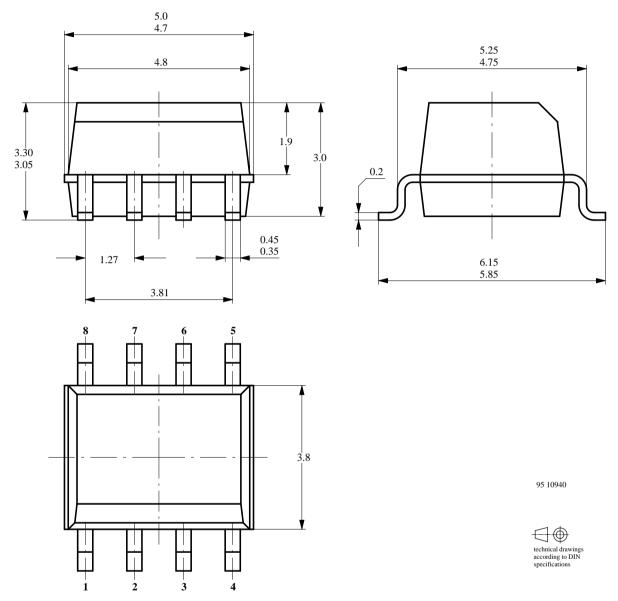
# **Current Transfer Ratio (CTR)**

Parameters	Test Conditions	Туре	Symbol	Min.	Тур.	Max.	Unit
I <sub>C</sub> /I <sub>F</sub>	$V_{CE} = 5 V,$	TCMT1020		0.2			
	$I_F = 10 \text{ mA}$	TCMT1021		0.4		0.8	
		TCMT1022	CTR	0.65		1.25	
		TCMT1023		1		2	
		TCMT1024		1.6		3.2	

# **TCMT1020 Series**

# TELEFUNKEN Semiconductors

#### **Dimensions in mm**



#### **Ozone Depleting Substances Policy Statement**

It is the policy of TEMIC TELEFUNKEN microelectronic GmbH to

- 1. Meet all present and future national and international statutory requirements.
- 2. Regularly and continuously improve the performance of our products, processes, distribution and operating systems with respect to their impact on the health and safety of our employees and the public, as well as their impact on the environment.

It is particular concern to control or eliminate releases of those substances into the atmosphere which are known as ozone depleting substances (ODSs).

The Montreal Protocol (1987) and its London Amendments (1990) intend to severely restrict the use of ODSs and forbid their use within the next ten years. Various national and international initiatives are pressing for an earlier ban on these substances.

**TEMIC TELEFUNKEN microelectronic GmbH** semiconductor division has been able to use its policy of continuous improvements to eliminate the use of ODSs listed in the following documents.

- 1. Annex A, B and list of transitional substances of the Montreal Protocol and the London Amendments respectively
- 2. Class I and II ozone depleting substances in the Clean Air Act Amendments of 1990 by the Environmental Protection Agency (EPA) in the USA
- 3. Council Decision 88/540/EEC and 91/690/EEC Annex A, B and C (transitional substances) respectively.

**TEMIC** can certify that our semiconductors are not manufactured with ozone depleting substances and do not contain such substances.

We reserve the right to make changes to improve technical design and may do so without further notice. Parameters can vary in different applications. All operating parameters must be validated for each customer application by the customer. Should the buyer use TEMIC products for any unintended or unauthorized application, the buyer shall indemnify TEMIC against all claims, costs, damages, and expenses, arising out of, directly or indirectly, any claim of personal damage, injury or death associated with such unintended or unauthorized use.

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